



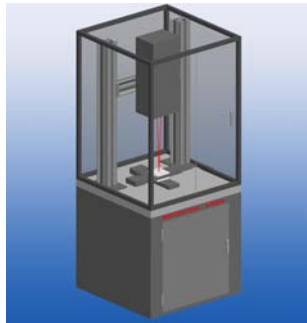
kSA 400 Features New 12-bit Camera!

In our continued efforts to improve the performance of the kSA 400 analytical RHEED system, k-Space has upgraded its standard camera to the K200D CCD camera. The K200D features 12-bit dynamic range, compact design and 640x480 pixel resolution at 50 frames per second (standard exposure time). The K200D connects through a single, small, high speed serial data cable, and offers full software control of all camera parameters, including exposure timing, gain, and shutter speed.



kSA MOS Ultra Scan

The MOS Ultra-Scan system has been demonstrated to several major semiconductor and flat panel display manufacturers and received excellent reviews. A new MOS Ultra-Scan system was installed in early October at Vieetech Japan Company's Process Integration Center (PIC) located in Mito Ibaraki, Japan. Vieetech has been a valued Asian distributor of k-Space products for over 10 years and prides itself in after-sales service and support. The complete line of k-Space products is available for demonstration at Vieetech's PIC. Please contact Vieetech directly (www.vieetech.co.jp) for further information or to schedule a demonstration.



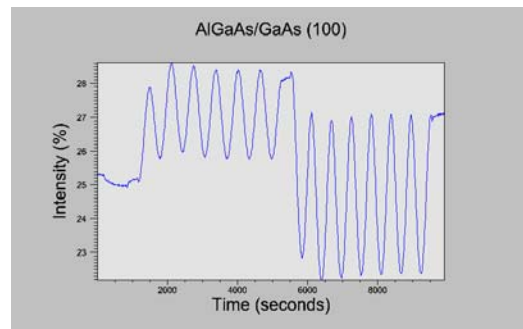
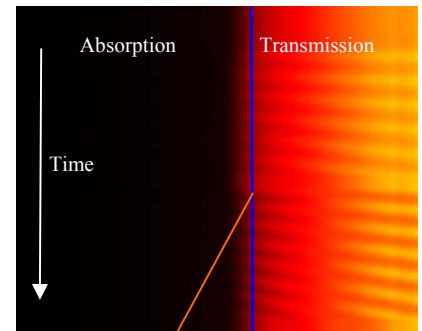
BandiT Light Source is Now Smaller!

k-Space has developed a new version of our BandiT light source. The new light source is significantly smaller in size while still retaining the same lighting intensity. Also new is the dual-axis tilt flange mount which allows greater control for easy alignment.



Growth Rate Determination with BandiT!

We have added the ability to determine deposition rate from the wavelength-dependent interference oscillations BandiT detects during heterostructure deposition. The figure below shows the evolution of the diffuse BandiT spectra as a function of deposition time. The spectra are stacked from top to bottom in the image, and the absorption edge is the vertical line between dark and light in the image. Clear oscillations in the transmission region can be seen, and these oscillations can be analyzed at each wavelength to accurately determine deposition rate. By using all the wavelengths present, we believe that we can converge on the deposition rate much more rapidly compared to standard pyrometric interference oscillations at a single wavelength.



Come See Us!

The k-Space staff enjoyed visiting the communities of Edinburgh, Scotland (2004 International MBE Conference) and Banff, Alberta, Canada (2004 North American MBE Conference). If you didn't stop by to say hello at one of these conferences, please be sure to visit us at one of the following upcoming conferences:

- **AVS Meeting 2004, Anaheim, California, Nov. 14-19, booth #611.**
- **MRS Fall Meeting, Boston, Massachusetts, Nov. 30 – Dec. 2, booth #801.**